

Simultaneous photon/particle counting and charge integration

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Purpose:
 Particle or photon counting pixels have a count rate limitation

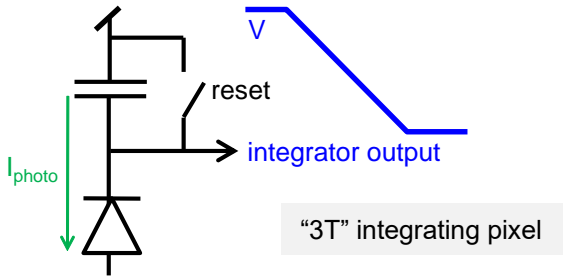
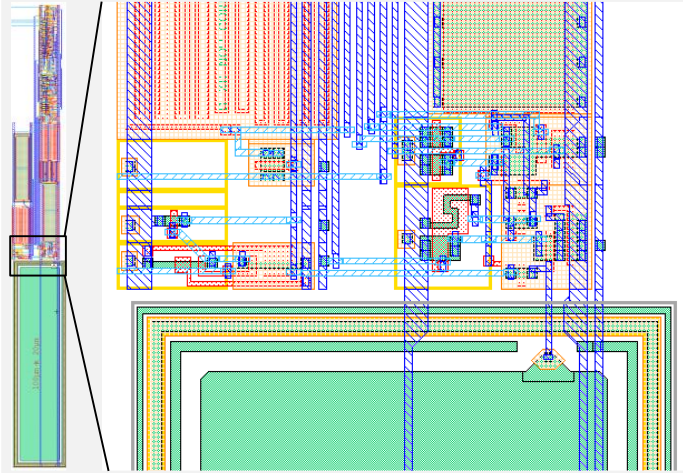
- Cannot distinguish close spaced hits
- Will saturate at high count rates or even
- paralyse at high count rates

How to recover information in such cases?

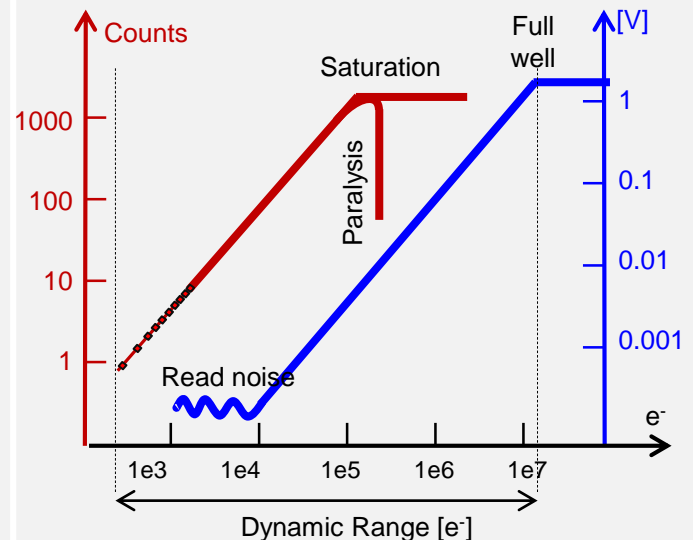
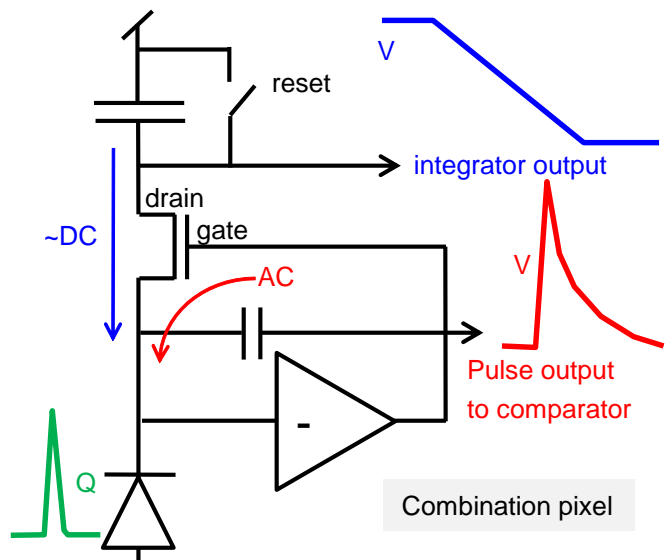
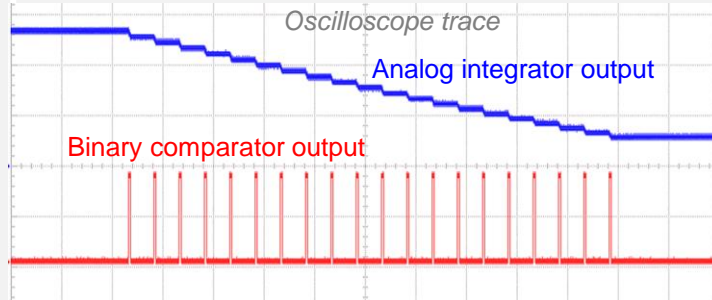
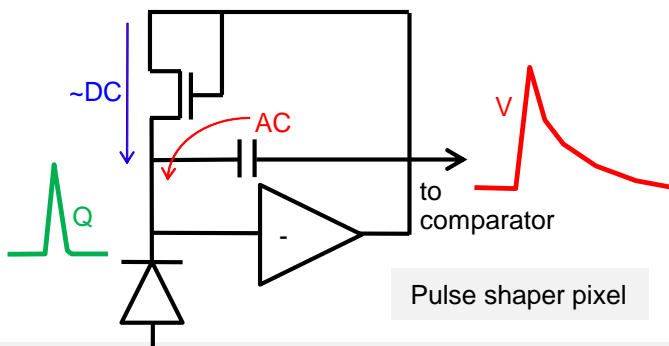
- Readout also the “old fashioned” integrated charge
- PRO: not hits lost, no paralysis
- CON: quantum limited noise is lost, individual particle information is lost (time, charge)

- Applications:**
- X-ray imaging, particle imaging
 - Spectroscopy in the presence of lines with highly different fluxes
 - Electron microscopy
 - Visible light imaging with SPADs

Prototype single pixel [1]
 XFAB XS018 technology
 Single pinned photodiode 20*100µm
 Contains both Pulse Shaper and Charge Integrator
 Analog readout of the Integrator
 Binary readout of the comparator (real time or latched)
 Integration capacitor = 1pF



Measured using LED pulses
 Minimum charge packet for reliable detection $\approx 350e^-$
 Max count rate $>100\text{kHz}$ (electronic channel limited)



[1] P.Gao & al, "Indirect X-ray Pixel with High Dynamic Range by using combined counting & integration", CNES workshop, Toulouse 17 Nov. 2016